

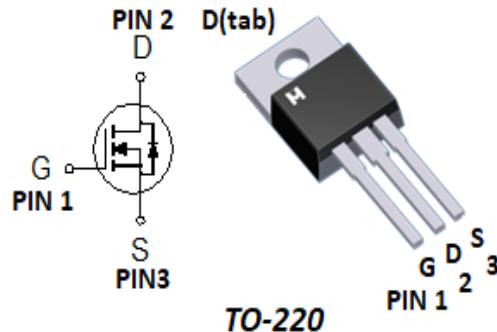
N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	150V
R _{DSON} (MAX.)	50mΩ
I _D	48A

UIS, Rg 100% Tested

RoHS & Halogen Free & TSCA Compliant

ABSOLUTE MAXIMUM RATINGS (T_c = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Drain-Source Voltage		V _{DSS}	150	V
Gate-Source Voltage		V _{GS}	±30	V
Continuous Drain Current	T _c = 25 °C	I _D	48	A
	T _c = 100 °C		30	
Pulsed Drain Current ¹		I _{DM}	140	
Avalanche Current		I _{AS}	18	
Avalanche Energy	L = 0.2mH, ID=18A, RG=25Ω	E _{AS}	32.4	mJ
Repetitive Avalanche Energy ²	L = 0.1mH	E _{AR}	16.2	
Power Dissipation	T _c = 25 °C	P _D	104	W
	T _c = 100 °C		41	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	1.2	62.5	°C / W
Junction-to-Ambient	R _{θJA}			

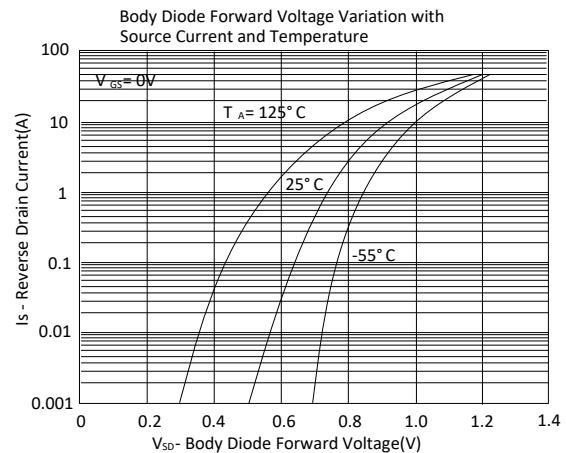
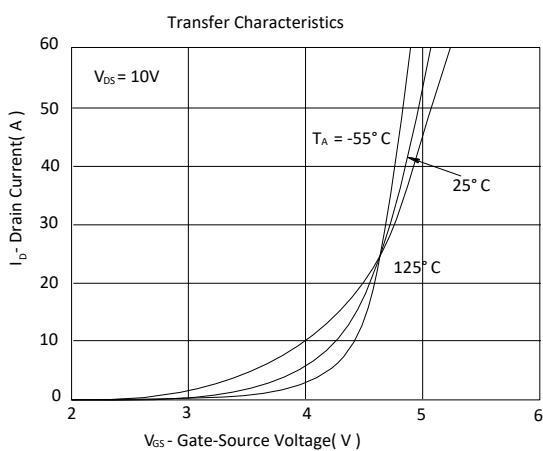
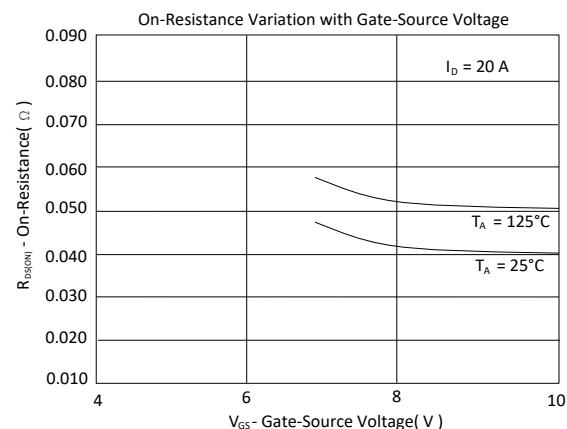
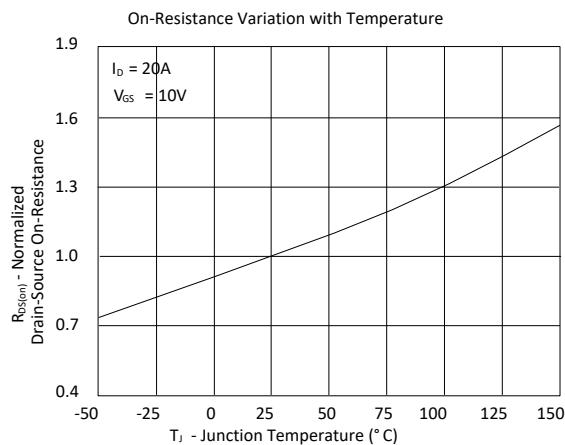
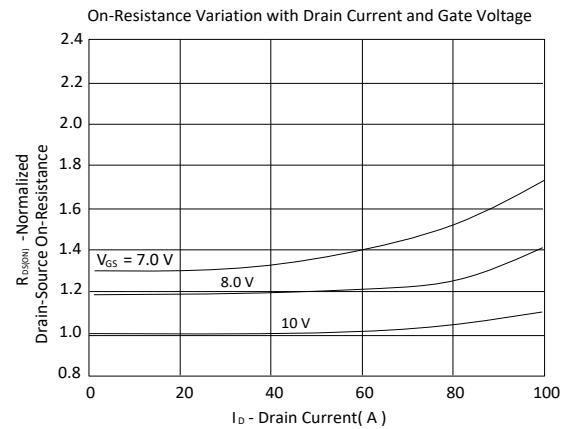
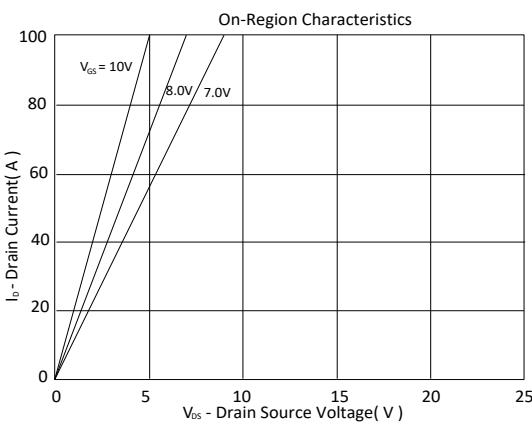
¹Pulse width limited by maximum junction temperature.²Duty cycle ≤ 1%

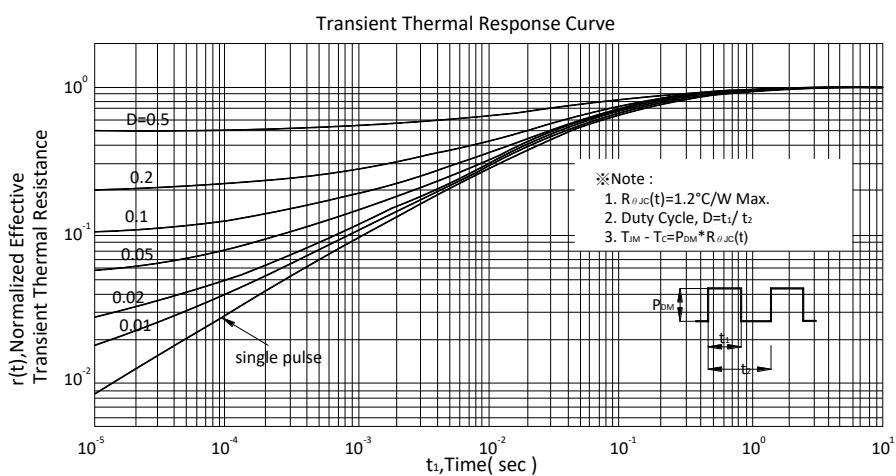
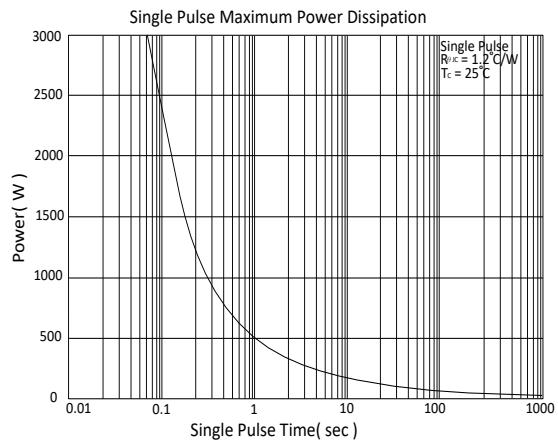
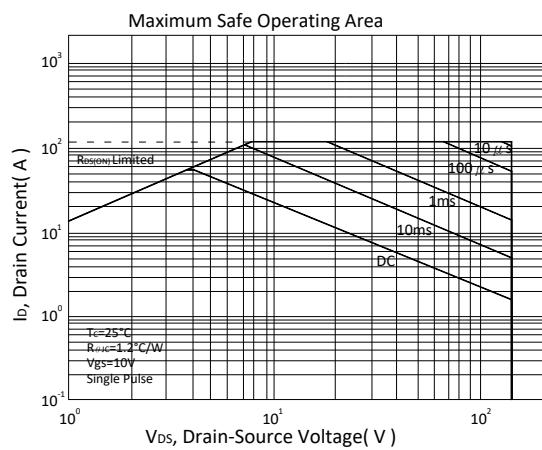
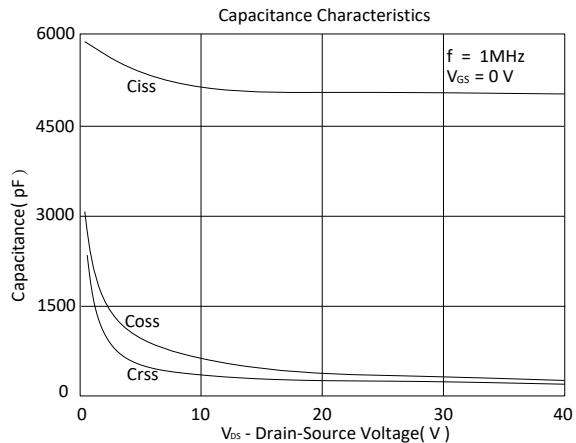
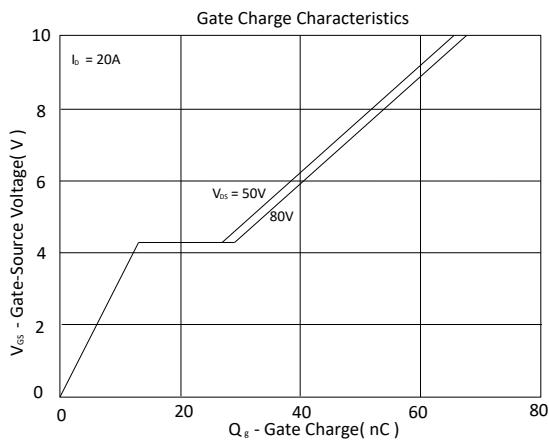
ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	150			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.5	2.5	4.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 120\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 100\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 10\text{V}$	48			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 20\text{A}$		40	50	$\text{m}\Omega$
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 20\text{A}$		40		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		4905		pF
Output Capacitance	C_{oss}			238		
Reverse Transfer Capacitance	C_{rss}			200		
Gate Resistance	R_g	$V_{\text{GS}} = 15\text{mV}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		2.0		Ω
Total Gate Charge ^{1,2}	Q_g	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 20\text{A}$		67.5		nC
Gate-Source Charge ^{1,2}	Q_{gs}			12.7		
Gate-Drain Charge ^{1,2}	Q_{gd}			16.6		
Turn-On Delay Time ^{1,2}	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 75\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 6\Omega$		20		nS
Rise Time ^{1,2}	t_r			18		
Turn-Off Delay Time ^{1,2}	$t_{\text{d}(\text{off})}$			40		
Fall Time ^{1,2}	t_f			18		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S				48	A
Pulsed Current ³	I_{SM}				140	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 25\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		120		nS
Reverse Recovery Charge	Q_{rr}			380		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

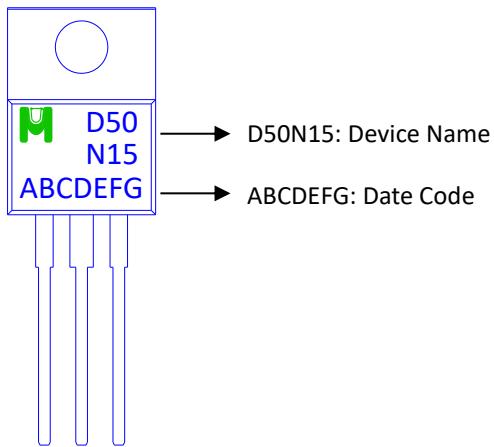
TYPICAL CHARACTERISTICS



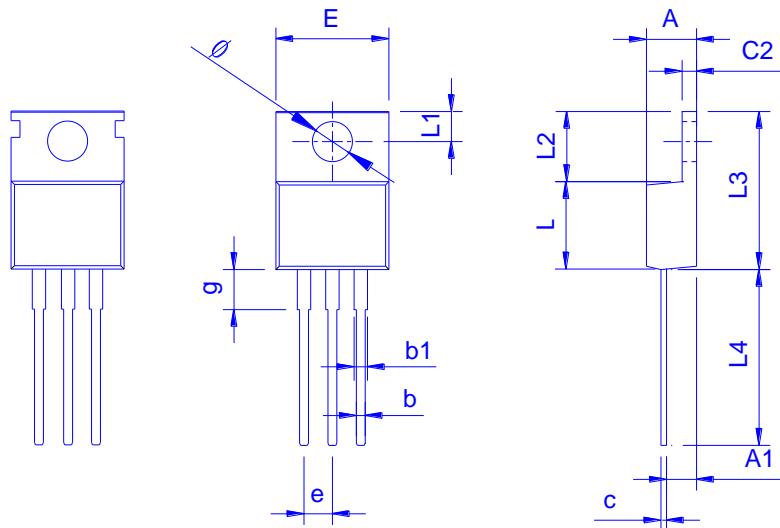


Ordering & Marking Information:

Device Name: EMD50N15E for TO-220



Outline Drawing



Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L	L1	L2	L3	L4	ϕ	e	g
Min.	4.240	2.250	0.700	1.170	0.310	1.150	9.910	8.500	2.590	6.100	14.700	12.700	3.400	2.440	2.850
Typ.	4.440	2.400	0.800	1.550	0.500	1.270	10.160	8.920	2.800	6.300	15.370	13.720	3.840	2.540	3.800
Max.	4.700	2.820	0.910	1.750	0.650	1.400	10.360	9.750	3.250	6.800	16.900	13.970	3.935	2.640	4.000

◆ Tube Information: 50pcs/Tube (1000pcs/Box)

